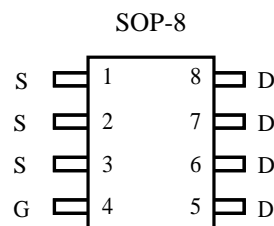


## N-Channel High Density Trench MOSFET

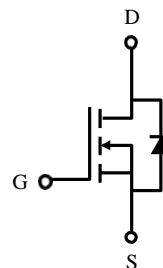
### Features:

- Super high dense cell trench design for low RDS(on).
- Rugged and reliable.
- Surface Mount package.



### PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(on)}$ (m $\Omega$ ) Max	$I_D$
30V	13 @ $V_{GS}=10V$	16A
	16 @ $V_{GS}=4.5V$	



### ABSOLUTE MAXIMUM RATINGS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous (Note 1) @ $T_A = 25\text{ }^\circ\text{C}$ -Pulse (Note 2)	$I_D$	16	A
	$I_{DM}$	60	
Maximum Power Dissipation (Note 1)	$P_D$	$T_A=25\text{ }^\circ\text{C}$	3.2
		$T_A=75\text{ }^\circ\text{C}$	2.0
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	- 55 to 150	$^\circ\text{C}$

### THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient (Note 1)	$R_{thJA}$	42	$^\circ\text{C/W}$
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Note:

1. Surface Mounted on FR4 Board ,  $t \leq 10\text{sec}$  .
2. Pulse width limited by maximum junction temperature

**ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)**

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 24V, V_{GS} = 0V$			1	$\mu A$
Gate-Body Leakage	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	nA
<b>ON CHARACTERISTICS (Note 3)</b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	1.6	3	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 15A$		11	13	m $\Omega$
		$V_{GS} = 4.5V, I_D = 9A$		13	16	m $\Omega$
Forward Transconductance	gfs	$V_{DS} = 15V, I_D = 12.5A$		12		S
<b>DYNAMIC CHARACTERISTICS (Note 4)</b>						
Input Capacitance	$C_{ISS}$	$V_{DS} = 10V, V_{GS} = 0V$ $f = 1.0MHz$		1094		pF
Output Capacitance	$C_{OSS}$			147		pF
Reverse Transfer Capacitance	$C_{RSS}$			127		pF
<b>SWITCHING CHARACTERISTICS (Note 4)</b>						
Turn-On Delay Time	$t_{d(ON)}$	$V_{DD} = 15V, I_D = 1A, V_{GEN} = 10V, R_{GEN} = 6\Omega, R_L = 15\Omega$		6		nS
Rise Time	$t_r$			22.5		nS
Turn-Off Delay Time	$t_{d(OFF)}$			48.6		nS
Fall Time	$t_f$			19.8		nS
Total Gate Charge	$Q_g$	$V_{DS} = 10V, I_D = 1A$ $V_{GS} = 10V$		31		nC
Gate-Source Charge	$Q_{gs}$			1.4		nC
Gate-Drain Charge	$Q_{gd}$			9.3		nC
<b>DRAIN-SOURCE DIODE CHARACTERISTICS</b>						
Drain-Source Diode Forward Current (Note 1)	$I_S$			8		A
Diode Forward Voltage (Note 3)	$V_{SD}$	$V_{GS} = 0V, I_S = 1.0A$		0.7	1.1	V

Note:

3. Pulse Test Pulse width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$ .

4. Guaranteed by design, not subject to production testing.

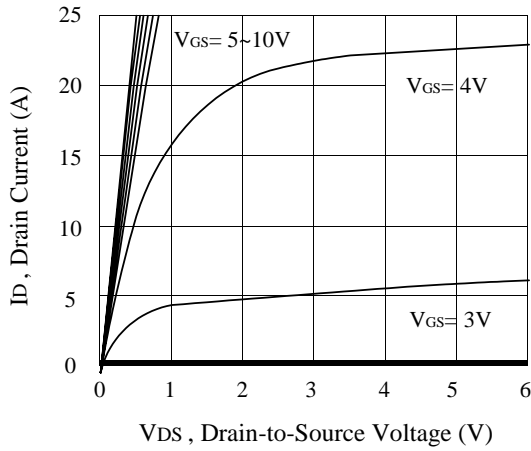


Figure 1. Output Characteristics

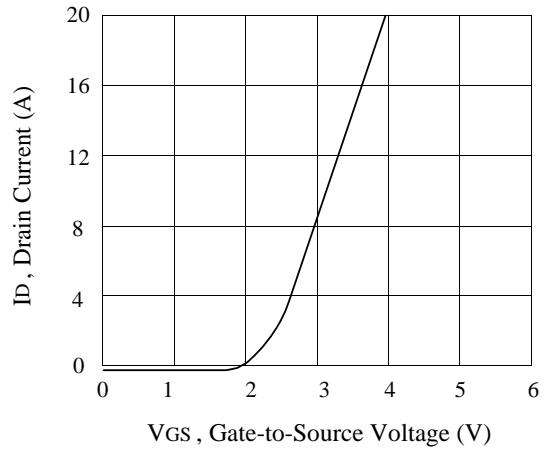


Figure 2. Transfer Characteristics

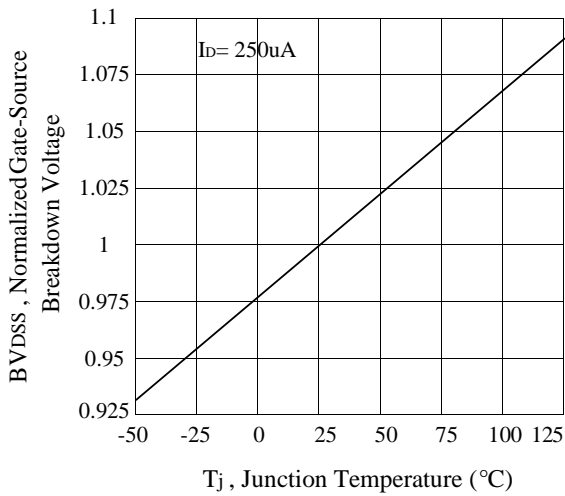


Figure 3. Breakdown Voltage Variation with Temperature

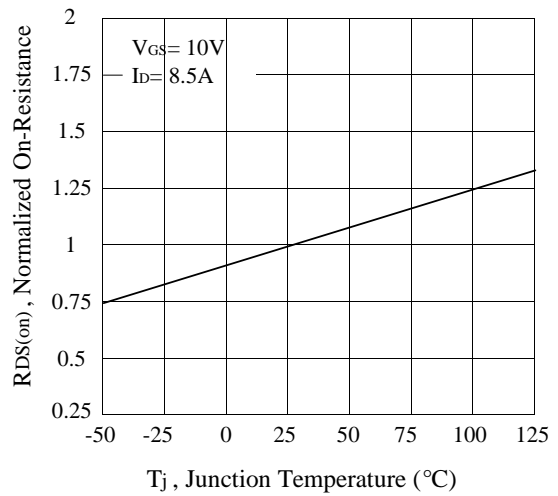


Figure 4. On-Resistance Variation with Temperature

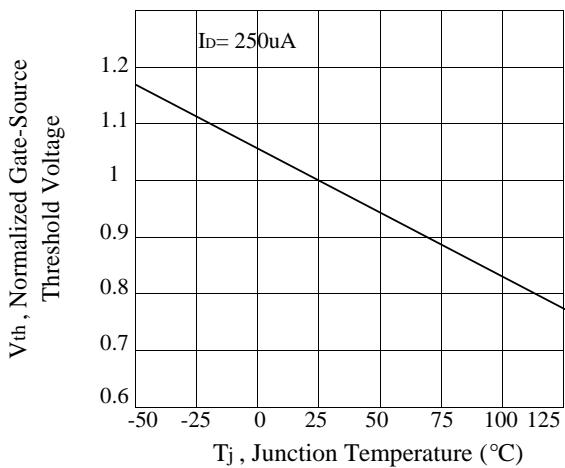


Figure 5. Gate Threshold Variation with Temperature

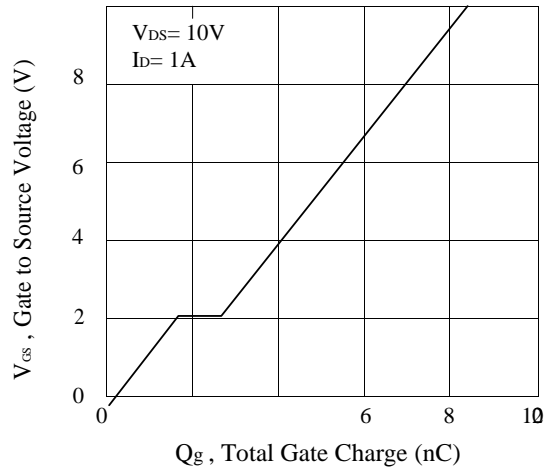
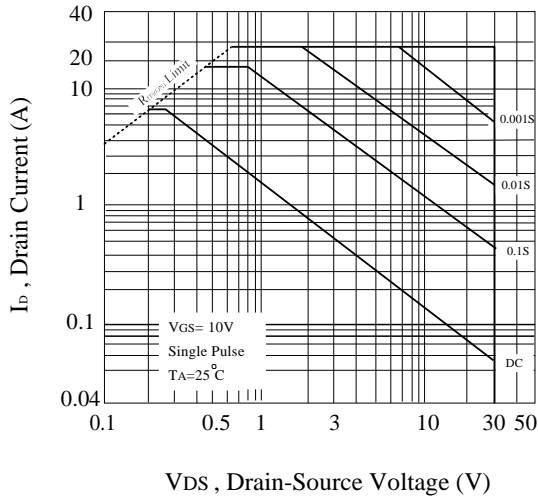
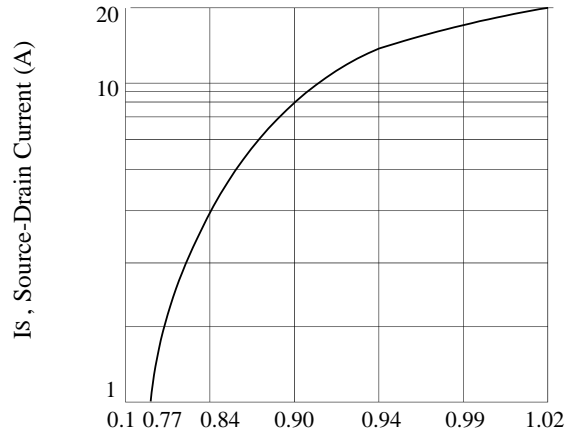


Figure 6. Gate Charge



VDS, Drain-Source Voltage (V)  
 Figure 7. Maximum Safe Operating Area



VSD, Body Diode Forward Voltage (V)  
 Figure 8. Body Diode Forward Voltage Variation with Source Current

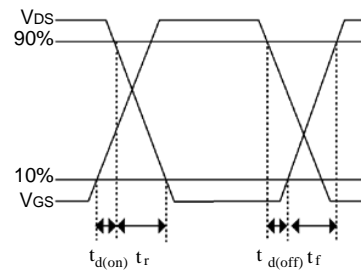
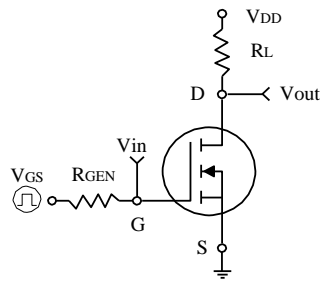


Figure 9. Switching Test Circuit and Switching Waveforms

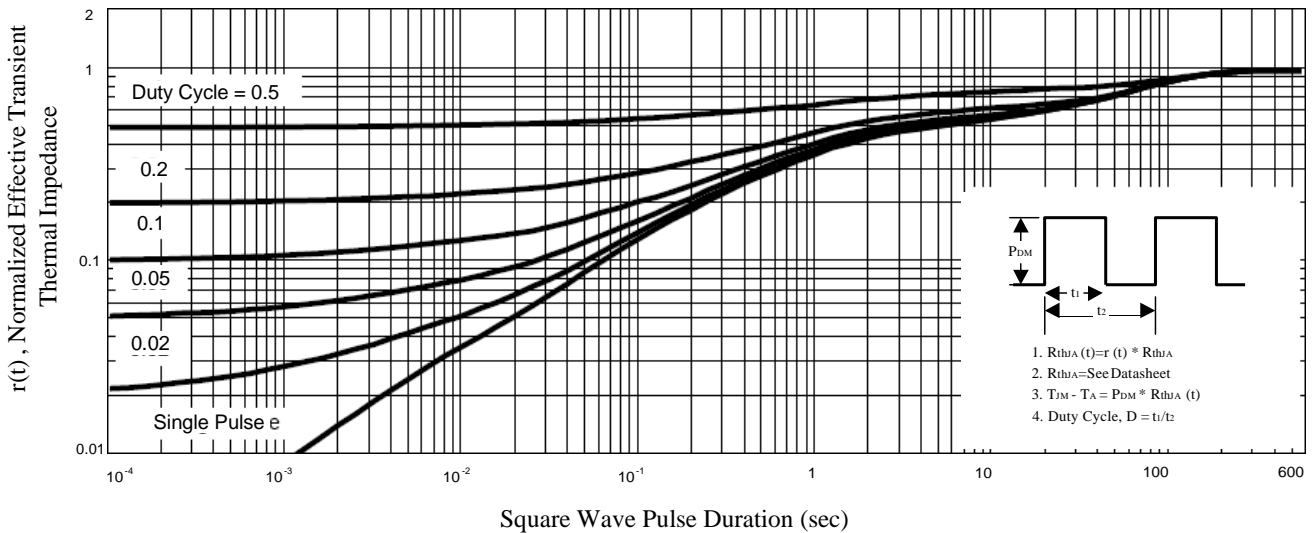


Figure 10. Normalized Thermal Transient Impedance Curve